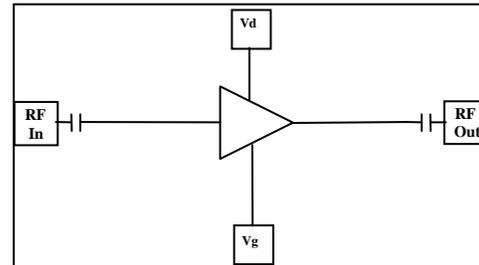


5 – 6 GHz 20dBm Gain block Amplifier

Features

- ◆ Frequency Range : 5 – 6GHz
- ◆ 21.5 dBm output P1dB
- ◆ 14 dB Power gain
- ◆ 30% PAE
- ◆ High IP3
- ◆ Input Return Loss > 12 dB
- ◆ Output Return Loss > 15 dB
- ◆ Dual bias operation
- ◆ No external matching required
- ◆ DC decoupled input and output
- ◆ 0.5 μ m InGaAs pHEMT Technology
- ◆ Chip dimension: 1.2 x 1.6 x 0.1 mm

Functional Diagram



Typical Applications

- ◆ RADAR
- ◆ Military & space
- ◆ LMDS, VSAT

Description

The AMT2133011 is a C-band Gain block amplifier with 20dBm power output. The PA operates in 5 – 6 GHz frequency range. The PA features 14 dB of gain with input and output return losses of 12 dB and 15 dB respectively. The PA has a high IP3 of 30dBm and 35% PAE. This feature enables it to be used in the applications requiring efficiency along with linearity. The chip operates with dual bias supply voltage. The die is fabricated using a reliable 0.5 μ m InGaAs pHEMT technology. The Circuit grounds are provided through vias to the backside metallization.

Absolute Maximum Ratings ⁽¹⁾

| Parameter | Absolute Maximum | Units |
|--------------------------------|------------------|-------|
| Drain bias voltage (Vd) | +8 | volts |
| Drain current (Idq) | 120 | mA |
| RF input power (RFIn at Vd=9V) | 23 | dBm |
| Operating temperature | -50 to +85 | °C |
| Storage Temperature | -65 to +150 | °C |

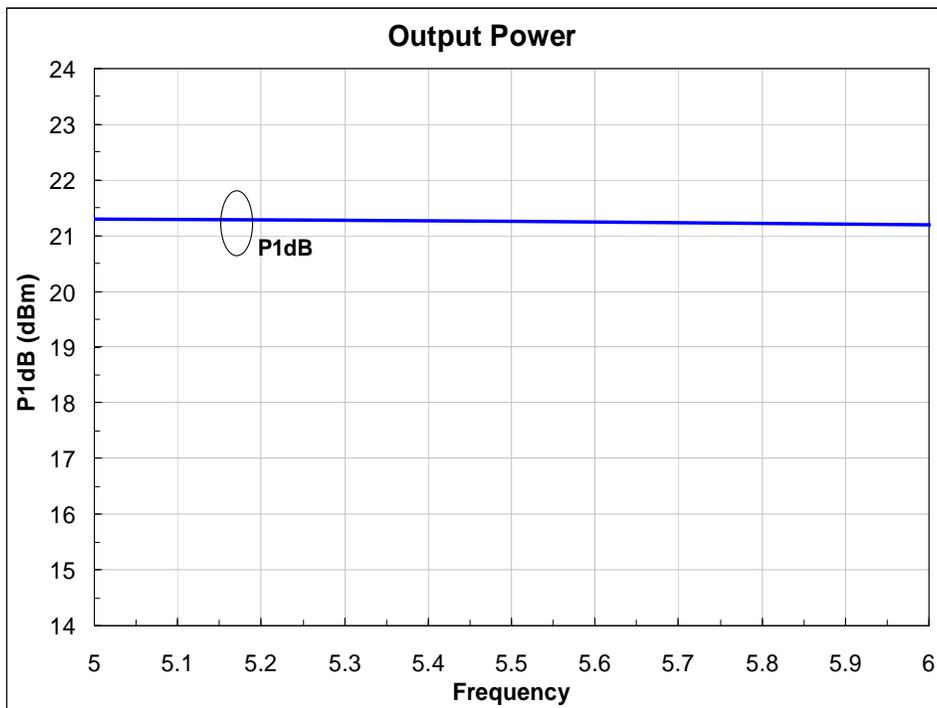
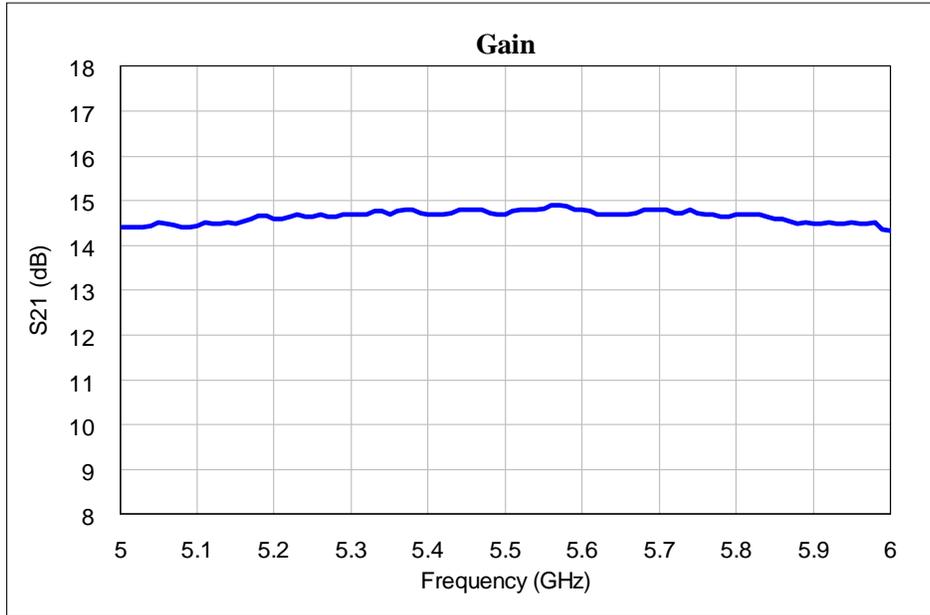
1. Operation beyond these limits may cause permanent damage to the component

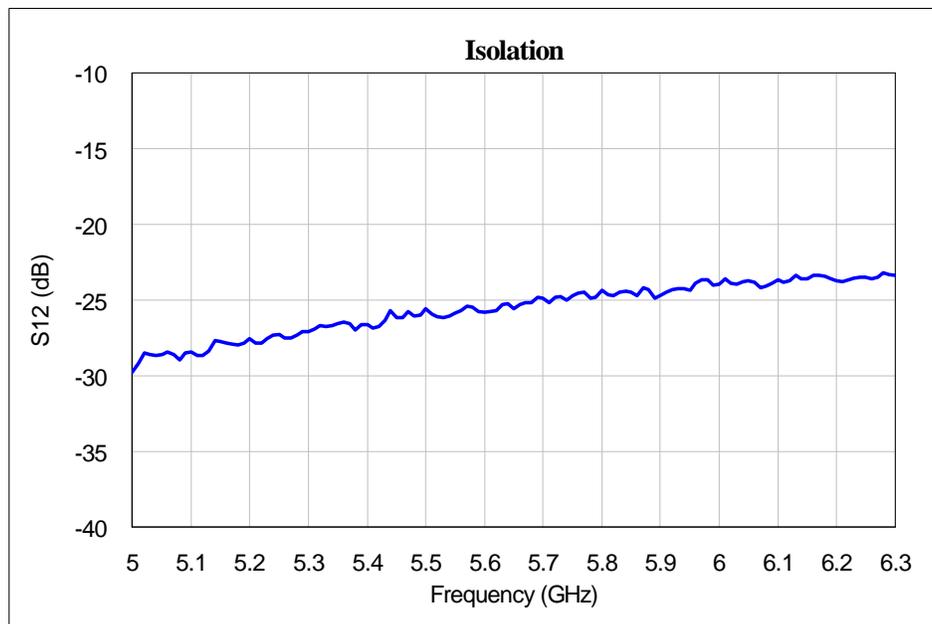
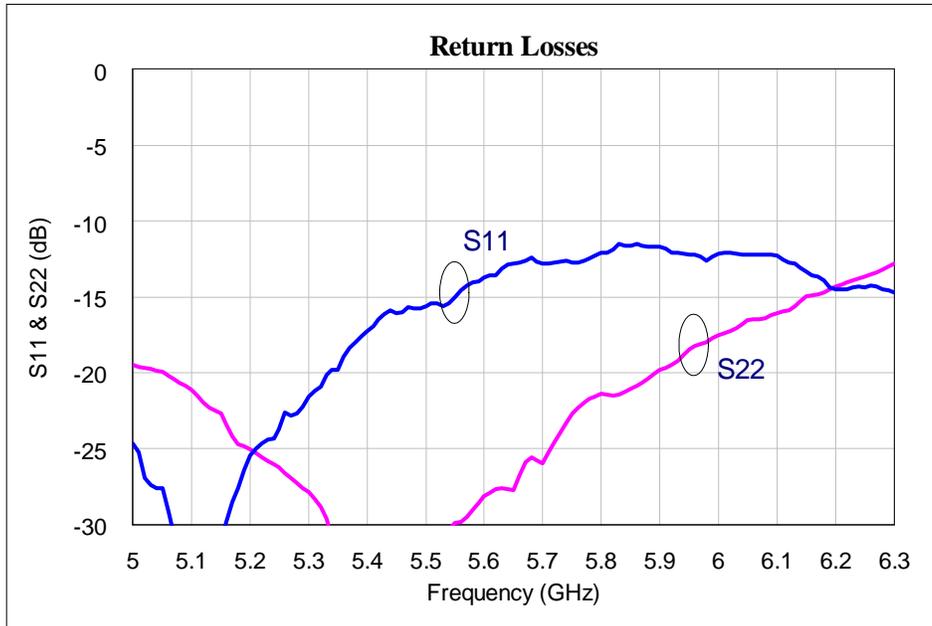
Electrical Specifications ⁽¹⁾ @ T_A = 25 °C, V_d = 8V, V_g = -0.9V, Z_o = 50 Ω

| Parameter | Typ. | Units |
|--|--------|-------|
| Frequency Range | 5 – 6 | GHz |
| Gain | 14 | dB |
| Gain Flatness | +/-0.3 | dB |
| Output Power (P1 dB) | 21.5 | dBm |
| Input Return Loss | 12 | dB |
| Output Return Loss | 15 | dB |
| Saturated output power (P _{sat}) | 22.5 | dBm |
| Output Third Order Intercept (IP3) | 30 | dBm |
| Power Added Efficiency (PAE) | 30% | -- |
| Supply Current(I _{dq}) | 60 | mA |

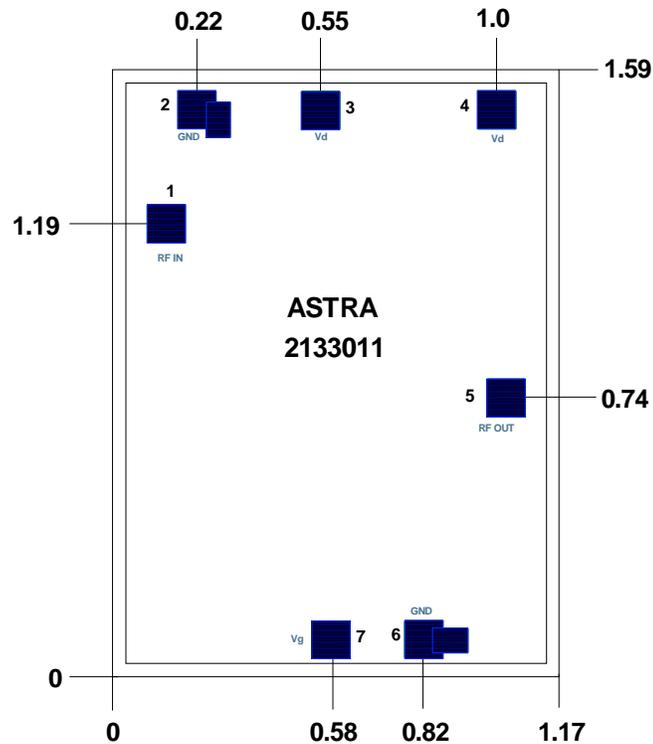
Note:

1. Electrical specifications as measured in test fixture.

Test fixture data $V_d = 8V$, $V_g = -0.9V$, Total Current = 60ma, $T_A = 25^\circ C$ 

Test fixture data
 $V_d = 8V, V_g = -0.9V, \text{Total Current} = 60\text{ma}, T_A = 25^\circ\text{C}$


Bond Pad Locations

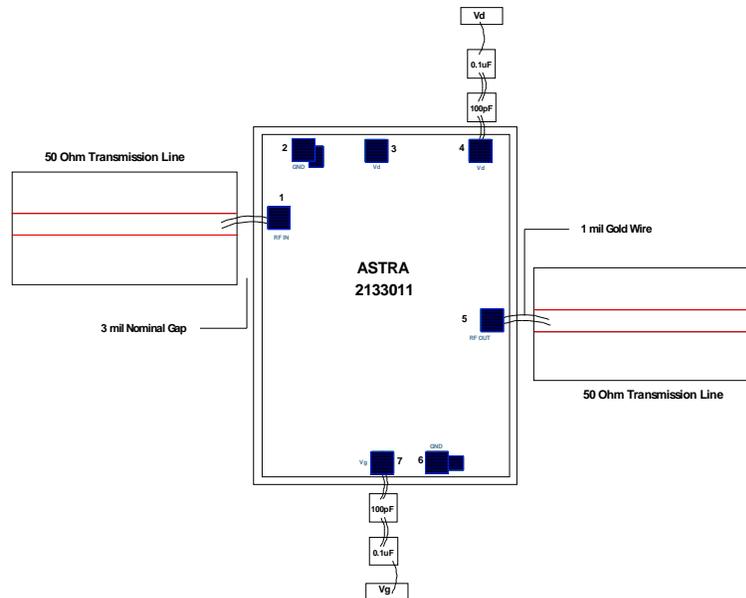


Units: millimeters

Note:

1. All RF and DC bond pads are 100µm x 100µm
2. Pad no. 1 : RF IN
3. Pad no. 4 : Drain voltage(V_d)
4. Pad no. 5 : RF Output
5. Pad no. 7 : Gate voltage (V_g)

Recommended Assembly Diagram



Note:

- Two 1 mil (0.0254mm) bond wires of minimum length should be used for RF input and output.
- Two 1 mil (0.0254mm) bond wires of minimum length should be used from chip bond pad to 100pF capacitor.
- Input and output 50 ohm lines are on 5 mil RT Duroid substrate
- 0.1 μ F capacitors may be additionally used as a second level of bypass for reliable operation
- The RF input & output ports are DC decoupled on-chip.
- Proper heat sink like Copper tungsten or copper molybdenum to be used for better reliability of chip

Die attach: For Epoxy attachment, use of a two-component conductive epoxy is recommended. An epoxy fillet should be visible around the total die periphery. If Eutectic attachment is preferred, use of fluxless AuSn (80/20) 1-2 mil thick preform solder is recommended. Use of AuGe preform should be strictly avoided.

Wire bonding: For DC pad connections use either ball or wedge bonds. For best RF performance, use of 150 - 200 μ m length of wedge bonds is advised. Single Ball bonds of 250-300 μ m though acceptable, may cause a deviation in RF performance.



GaAs MMIC devices are susceptible to Electrostatic discharge. Proper precautions should be observed during handling, assembly & testing

All information and Specifications are subject to change without prior notice